

PATENT  
450100-05490

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE 10/591204

Applicants: Sakae OKAZAKI et al.  
International Application No.: PCT/JP05/01391  
International Filing Date: February 1, 2005  
For: AUTOFOCUS-CONTROL DEVICE AND AUTOFOCUS-  
CONTROL METHOD, RECORDING MEDIUM, AND  
PROGRAM

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Sir:

Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP05/01391. Also enclosed is a copy of Form PTO-1449 and the International Search Report.


**REMARKS**

Entry of this Information Disclosure Statement and an early examination on the merits  
are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

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Enclosures

Based on Form PTO-1449 (3/90)	ATTY. DOCKET NO. 450100-05490	INTERNATIONAL SERIAL NO. PCT/JP05/01290
	APPLICANT Sakae OKAZAKI et al.	
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LIST OF REFERENCES CITED BY APPLICANT  
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6 222 588	04/24/01	Yamazaki et al.			
	AB	6 184 932	02/06/01	Tanaka			
	AC						
	AD						
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AE	7 170439	07/04/95	Japan			
	AF	7 154676	06/16/95	Japan			
	AG	5 107451	04/30/93	Japan			
	AH	6 339059	12/06/94	Japan			
	AI	2000 333072	11/30/00	Japan			
	AJ	2001 86389	03/30/01	Japan			
	AK	2001 4914	01/12/01	Japan			
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	AM	11 153748	06/08/99	Japan			
	AN	8 265619	10/11/96	Japan			
	AO	60 32482	02/19/85	Japan			
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